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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Paul F. Fewster, et al.

Divisional of Serial No.: 10/022,150

For: **X-RAY DIFFRACTOMETER**

Examiner: Allen C. HO

Art Group: 2882

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Arlington, VA 22313-1450

Dear Sir:

In accordance with 37 CFR 1.56, Applicant hereby discloses the prior art references that have been submitted and/or cited in the following related application/patent:

Serial No.	Filing Date	Patent No.	Issue Date
10/022,150	12/13/2001	---	---

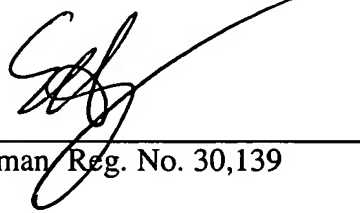
Form PTO/SB/08B(substitute for form 1449A/PTO) is enclosed herewith. Copies of the references are not provided as permitted by 37 CFR 1.98(d).

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN

Date: March 16, 2004

12400 Wilshire Boulevard
Seventh Floor
Los Angeles, California 90025
(310) 207-3800

By: 
Eric S. Hyman, Reg. No. 30,139

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV.7-80) PATENT AND TRADEMARK OFFICE										Atty. Docket No. GB 000180		Serial No.	
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)										Applicant PAUL F. FEWSTER et al.			
										Filing Date CONCURRENTLY		Group	

U.S. PATENT DOCUMENTS															
Ex. Int.		Document Number								Date	Name	Class	Sub-class	Filing Date If Approp.	
	AA														
	AB														
	AC														
	AD														
	AE														
	AF														

FOREIGN PATENT DOCUMENTS															
		Document Number								Date	Country	Class	Sub-class	Trans.	
														Yes	No
	AG	0	3	1	8	0	1	2	A 2	5/31/89	EUROPE	G01N	23/207	X	
	AH	A	0	1	2	7	0	6	.5 0	10/27/89	Japan (Abstract)	G01N	23/207	X	
	AI	A	0	1	2	7	6	0	5 2	11/6/89	Japan (Abstract)	G01N	23/207	X	
	AJ														
	AK														

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)															
	AL	"Characterization of Thin Layers on Perfect Crystals with a Multipurpose High Resolution X-ray Diffractometer", Bartels, Journal Vacuum Science and Technology B Volume 1 page 338 (1983).													
	AM														
	AN														

Examiner	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

OCT 25 2002

Sheet 1 of 1

U.S. DEPARTMENT OF COMMERCE
(REV. 7-80) PATENT AND TRADEMARK OFFICE

Atty. Docket No.
GB000180

Serial No.
10/022,150

Applicant
Paul F. Fewster, et.al.

Filing Date
December 13, 2001

Group
2882

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

Ex. Int		Document Number	Date	Name	Class	Sub- class	Filing Date If Approp.
ACH	AA	5 8 5 0 4 2 5	12/15/1998	Wilkins	378	85	
ACH	AB	5 8 7 8 1 0 6	3/2/1999	Fujiwara	378	79	
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub- class	Trans.
							Yes No
	AG						
	AH						
	AI						
	AJ						
	AK						

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)

	AL	
	AM	
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Examiner

Allen C Ho

Date Considered

6/9/03

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Notice of References Cited

Application/Control No.

10/022,150

Applicant(s)/Patent Under
Reexamination
FEWSTER ET AL.

Examiner

Allen C. Ho

Art Unit

2882

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,226,349 B1	05-2001	Schuster et al.	378/84
	B	US-5,878,106	03-1999	Fujiwara	378/79
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	B. D. Cullity. Elements of X-Ray Diffraction, second edition (Reading, MA: Addison-Wesley, 1978), p. 156-158.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV.7-80) PATENT AND TRADEMARK OFFICE				Atty. Docket No. GB 000180		Serial No.	
				Applicant PAUL F. FEWSTER et al.			
				Filing Date CONCURRENTLY		Group	

Jc973 U.S. PTO
10/022150
 12/13/01

U.S. PATENT DOCUMENTS														
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ACH	AL	"Characterization of Thin Layers on Perfect Crystals with a Multipurpose High Resolution X-ray Diffractometer", Bartels, Journal Vacuum Science and Technology B Volume 1 page 338 (1983).
	AM	
	AN	

Examiner <u>Allen C. Ho</u>	Date Considered <u>9/30/02</u>
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Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	Atty. Docket No. GB000180	Serial No. 10/022,150
	Applicant Paul F. Fewster, et.al.	
	Filing Date December 13, 2001	Group 2882

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